Search Notes		

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/605,726	ZHU ET AL.	
Examiner	Art Unit	
Stephen W. Smoot	2813	

SEARCHED				
Class	Subclass	Date	Examiner	
438	151	2/5/2005	sws	
438	270	2/5/2005	sws	
438	295	2/5/2005	sws	
438	300	2/5/2005	sws	
438	589	2/5/2005	sws	
438	595	2/5/2005	sws	
257	347	2/5/2005	sws	
257	387	2/5/2005	sws	
Updated	Above	5/26/2005	sws	
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
			044-0	
Same as Above		5/26/2005	S.W.S.	

SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
Key Words: SOI - BOX, SiGe, Silicon Epitaxial Layer;	2/5/2005	S.W.f.
Elevated Source/Drain - Raised; Recessed Gate - Trench, Groove, Damascene, Inlaid.	2/5/2005•	I.V.I
Updated Above Search	5/26/2005	INI.
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Search Tools - EAST (attached): USPAT; US PG PUBS; Derwent; EPO; JPO; IBM TDB	2/5/2005 & 5-26-05	sws